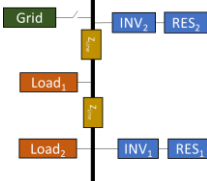


(2) test case description: use the following HTD canvas]

Title: Dynamic Characterization of Power-Electronics-based-Microgrid (Dyn-PEM)		Author: Salman Harasis Date: September 2 nd , 2022	
Test Objectives Why is the test needed? What do we expect to find out? <u>Ans:</u> <ul style="list-style-type: none"> Characterization and testing of DGs dynamic performance for better system dynamic evaluation. Measuring and quantifying the available inertia level in the system. Evaluation of the optimal mix of grid forming and grid feeding DGs under dynamic operating conditions. Emulation some grid anomalies (e.g., sag, swell, and flickering). 		Purpose of Investigation (PoI) The test purposes classified in with terms <i>Characterization</i> , <i>Verification</i> , or <i>Validation</i> <u>Ans:</u> <ul style="list-style-type: none"> Determination of the optimal operating modes of different DERs under certain system configuration, load type, and type of sources. Characterization and verification of system response under different DG types, Grid feeding, grid forming. Validation of the simulation results under realistic grid conditions. characterization of the frequency dynamics according to the system specifications. 	
Object under Investigation (Oul) "the component(s) (1..n) that are to be qualified by the test" <ul style="list-style-type: none"> A microgrid system that contains ≥2 DGs The existence of grid emulator Distribution lines Power, voltage, and frequency signals. 	Function(s) under Investigation (Ful) "The referenced specification of a function realized (operationalized) by the object under investigation" <ul style="list-style-type: none"> Microgrid system level and device level optimization Inertia quantification of microgrid 	System under Test (SuT) Systems, subsystems, components included in the test case or test setup. <ul style="list-style-type: none"> DGs with known capacities, source type (or emulated). distribution lines. Fixed load. Variable load (programmable is preferred). <p>(Possible configuration of the microgrid under study)</p> 	Functions under Test (Fut) Functions relevant to the operation of the system under test, including Ful and relevant interactions btw. Oul and SuT. <ul style="list-style-type: none"> DGs with Q-V and P-f controllers. DGs works under different loading conditions (by having variable loads), DGs with their power/voltage/frequency are accessed to be measured. (Instantaneous current and voltage signals).
Domain under Investigation (Dul) "the relevant domains or sub-domains of test parameters and connectivity." <ul style="list-style-type: none"> Low voltage electric power domain that includes measured ac voltage, ac current, dc voltage. Control domain. 			
Test criteria (TCR) Formulation of criteria for each PoI based on properties of SuT; encompasses properties of test signals and output measures. <ul style="list-style-type: none"> instantaneous voltage and current profiles of each DG, the impedance of the lines, the dc link voltage and frequency measurement. transient response of a step load change (includes current overshoot, settling time). plug and play capability of DER. 			
target metrics Measures required to quantify each identified test criteria <ul style="list-style-type: none"> ΔP (the difference between the actual and scheduled power) Δf (the difference between the actual and nominal frequency) ΔV (the voltage deviation) Actual inertia value calculated/measured. 	variability attributes controllable or uncontrollable factors and the required variability; ref. to PoI. <ul style="list-style-type: none"> Realistic PV generation and load variation. Communication delay. 	quality attributes threshold levels for test result quality as well as pass/fail criteria. <ul style="list-style-type: none"> Restoring the original operating conditions after clearing a disturbance. (Successful test). System frequency and voltage restoration under dynamic conditions (≤10 seconds). (Successful test). 	